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FODM121 Series, FODM124, FODM2701, FODM2705 4-Pin Full Pitch Mini-Flat Package Phototransistor Optocouplers

Features

- More than 5 mm Creepage/Clearance
- Compact 4-Pin Surface Mount Package (2.4 mm Maximum Standoff Height)
- Current Transfer Ratio in Selected Groups: DC Input: FODM121: 50–600%

FODM121A: 100–300% FODM121B: 50–150% FODM121C: 100–200% FODM124: 100% MIN FODM2701: 50–300% AC Input: FODM2705: 50–300%

Safety and Regulatory Approvals:

- UL1577, 3,750 VAC_{RMS} for 1 Minute
- DIN-EN/IEC60747-5-5, 565 V Peak Working Insulation Voltage

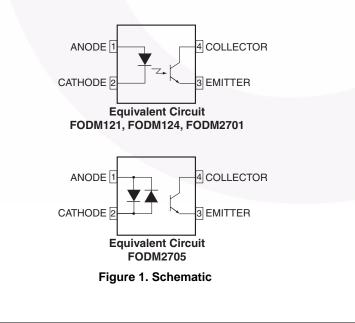
Applications

- Digital Logic Inputs
- Microprocessor Inputs
- Power Supply Monitor
- Twisted Pair Line Receiver
- Telephone Line Receiver

Description

The FODM121 series, FODM124, and FODM2701 consists of a gallium arsenide infrared emitting diode driving a phototransistor in a compact 4-pin mini-flat package. The lead pitch is 2.54 mm. The FODM2705 consists of two gallium arsenide infrared emitting diodes connected in inverse parallel for AC operation.

Functional Block Diagram



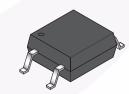


Figure 2. Package Outlines

November 2015

Safety and Insulation Ratings

As per DIN EN/IEC 60747-5-5, this optocoupler is suitable for "safe electrical insulation" only within the safety limit data. Compliance with the safety ratings shall be ensured by means of protective circuits.

Parameter		Characteristics
Installation Classifications per DIN VDE	< 150 V _{RMS}	I–IV
0110/1.89 Table 1, For Rated Mains Voltage	< 300 V _{RMS}	I–III
Climatic Classification	40/110/21	
Pollution Degree (DIN VDE 0110/1.89)		2
Comparative Tracking Index		175

Symbol	Parameter	Value	Unit
M	Input-to-Output Test Voltage, Method A, $V_{IORM} \times 1.6 = V_{PR}$, Type and Sample Test with t _m = 10 s, Partial Discharge < 5 pC	904	V _{peak}
V _{PR}	Input-to-Output Test Voltage, Method B, $V_{IORM} \times 1.875 = V_{PR}$, 100% Production Test with $t_m = 1 \text{ s}$, Partial Discharge < 5 pC	1060	V _{peak}
VIORM	Maximum Working Insulation Voltage	565	V _{peak}
V _{IOTM}	Highest Allowable Over-Voltage	6000	V _{peak}
	External Creepage	≥ 5	mm
	External Clearance	≥ 5	mm
DTI	Distance Through Insulation (Insulation Thickness)	≥ 0.4	mm
Τ _S	Case Temperature ⁽¹⁾	150	°C
I _{S,INPUT}	Input Current ⁽¹⁾	200	mA
P _{S,OUTPUT}	Output Power ⁽¹⁾	300	mW
R _{IO}	Insulation Resistance at T _S , V_{IO} = 500 V ⁽¹⁾	> 10 ⁹	Ω

Note:

1. Safety limit values - maximum values allowed in the event of a failure.

Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only. $T_A = 25^{\circ}C$ Unless otherwise specified.

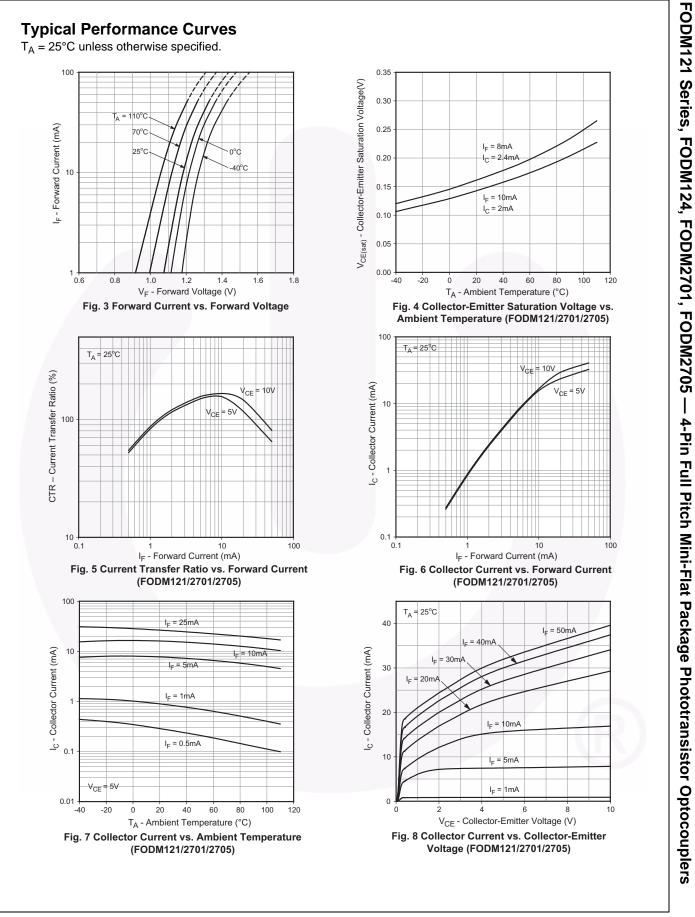
Symbol	Paran	Value	Unit	
TOTAL PACKA	NGE		I	
T _{STG}	Storage Temperature		-40 to +125	°C
T _{OPR}	Operating Temperature		-40 to +110	°C
ТJ	Junction Temperature		-40 to +125	°C
T _{SOL}	Lead Solder Temperature		260 for 10 sec	°C
EMITTER				
I _{F (avg)}	Continuous Forward Current		50	mA
I _{F (pk)}	Peak Forward Current (1 µs puls	e, 300 pps.)	1	А
V _R	Reverse Voltage		6	V
Р	Power Dissipation		70	mW
PD	Derate linearly (Above 75°C)	1.41	mW/°C	
DETECTOR				
Ι _C	Continuous Collector Current		80	mA
V _{CEO}	Collector-Emitter Voltage	FODM121 Series, FODM124	80	V
		FODM2701, FODM2705	40	
V _{ECO}	Emitter-Collector Voltage		6	V
P _D	Power Dissipation		150	mW
	Derate linearly (Above 80°C)		3.27	mW/°C

Symbol	Parameter	Device	Test Conditions	Min.	Тур.	Max.	Unit	
INDIVIDU	AL COMPONENT CHAR	ACTERISTICS					I	
Emitter								
		FODM121 Series, FODM124	I _F = 10 mA	1.0		1.3		
V _F	Forward Voltage	FODM2701	I _F = 5 mA			1.4	V	
		FODM2705	$I_F = \pm 5 \text{ mA}$					
I _R	Reverse Current	FODM121 Series, FODM124, FODM2701				5	μA	
Detecto	r							
B\/	Collector-Emitter	FODM121 Series, FODM124		80			v	
BV _{CEO}	Breakdown Voltage	FODM2701, FODM2705	I _C = 1 mA, I _F = 0	40			V	
BV _{ECO}	Emitter-Collector Breakdown Voltage	All	$I_{E} = 100 \ \mu A, \ I_{F} = 0$	7			V	
I _{CEO}	Collector Dark Current	All	$V_{CE} = 40 \text{ V}, I_{F} = 0$			100	nA	
C _{CE}	Capacitance	All	$V_{CE} = 0 V, f = 1 MHz$		10		pF	
TRANSFE	ER CHARACTERISTICS							
		FODM2701	$I_F = 5 \text{ mA}, V_{CE} = 5 \text{ V}$	50		300		
		FODM2705	$I_F = \pm 5 \text{ mA}, V_{CE} = 5 \text{ V}$	50		300	%	
		FODM121	I _F = 5 mA, V _{CE} = 5 V	50		600		
CTR	DC Current Transfer	FODM121A		100		300		
OIK	Ratio	FODM121B	F = 0 mA, VCE = 0 V	50		150		
		FODM121C				200		
		FODM124 $I_F = 1 \text{ mA}$	$I_{F} = 1 \text{ mA}, V_{CE} = 0.5 \text{ V}$	100		1200		
		1 ODMIZ I	$I_{F} = 0.5 \text{ mA}, V_{CE} = 1.5 \text{ V}$	50				
	CTR Symmetry	FODM2705	$I_F = \pm 5$ mA, $V_{CE} = 5$ V	0.3		3.0		
		FODM121 Series	$I_{F} = 8 \text{ mA}, I_{C} = 2.4 \text{ mA}$			0.4		
V _{CE(SAT)}	Saturation Voltage	FODM124	$I_{\rm F} = 1 \text{ mA}, I_{\rm C} = 0.5 \text{ mA}$			0.4	v	
VCE(SAT)	Saturation voltage	FODM2701	$I_{F} = 10 \text{ mA}, I_{C} = 2 \text{ mA}$			0.3		
		FODM2705	$I_F = \pm 10 \text{ mA}, I_C = 2 \text{ mA}$			0.3		
t _r	Rise Time (Non-Saturated)	All	$I_{C} = 2 \text{ mA}, \text{ V}_{CE} = 5 \text{ V},$ $R_{L} = 100 \Omega$		3		μs	
t _f	Fall Time (Non-Saturated)	All	$ I_{C} = 2 \text{ mA}, \text{V}_{CE} = 5 \text{ V}, \\ \text{R}_{L} = 100 \Omega $		3		μs	
SOLATIC	ON CHARACTERISTICS							
V _{ISO}	Steady State Isolation Voltage ⁽²⁾	All	1 minute	3750			VACRN	

Note:

2. Steady state isolation voltage, V_{ISO}, is an internal device dielectric breakdown rating. For this test, pins 1 and 2 are common, and pins 3 and 4 are common.

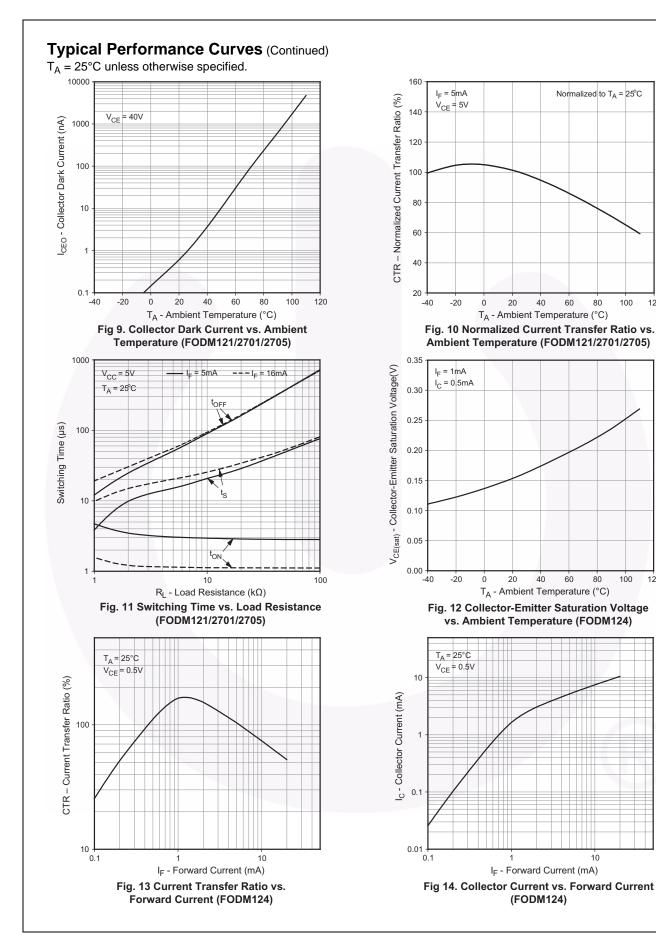
FODM121 Series, FODM124, FODM2701, FODM2705 — 4-Pin Full Pitch Mini-Flat Package Phototransistor Optocouplers

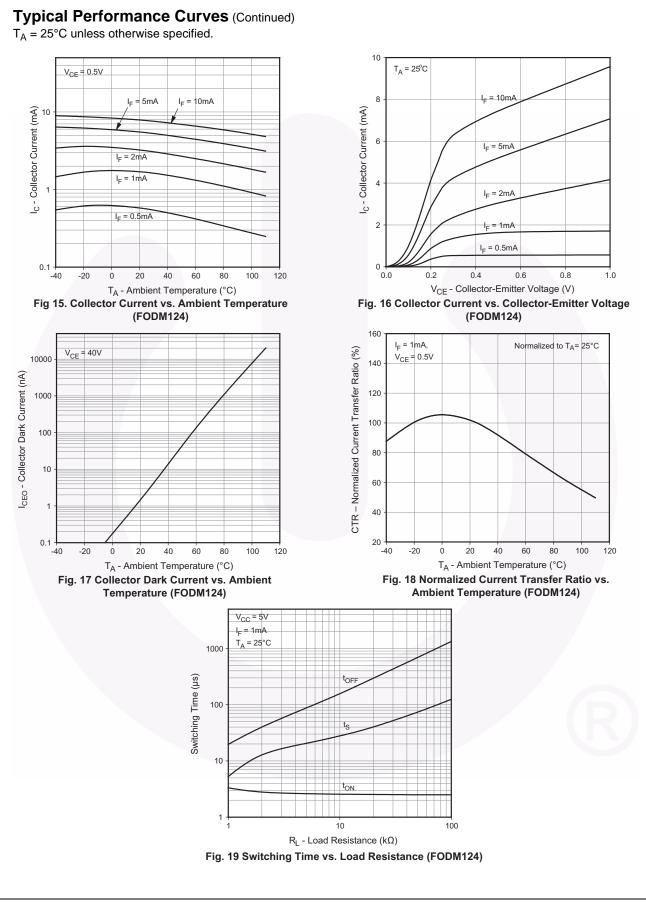


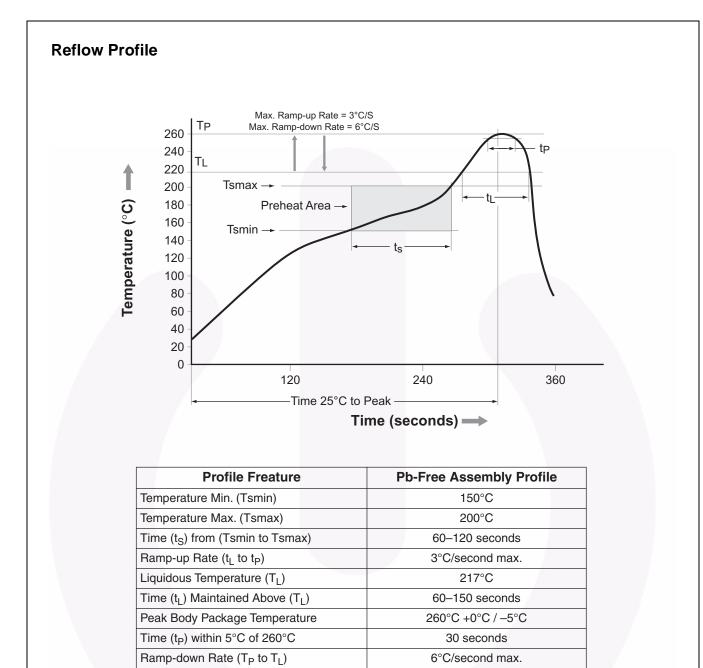


120

120







Time 25°C to Peak Temperature

8 minutes max.

Ordering Information

Part Number	Package	Packing Method
FODM121	Full Pitch Mini-Flat 4-Pin	Tube (100 units)
FODM121R2	Full Pitch Mini-Flat 4-Pin	Tape and Reel (2500 Units)
FODM121V	Full Pitch Mini-Flat 4-Pin, DIN EN/IEC60747-5-5 Option	Tube (100 Units)
FODM121R2V	Full Pitch Mini-Flat 4-Pin, DIN EN/IEC60747-5-5 Option	Tape and Reel (2500 Units)

Note:

The product orderable part number system listed in this table also applies to the FODM121A, FODM121B, FODM121C, FODM124, FODM2701, and FODM2705 products.

Marking Information

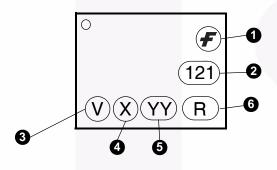
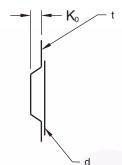


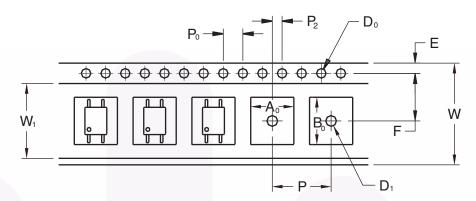
Figure 20. Top Mark

Table 1. Top Mark Definitions

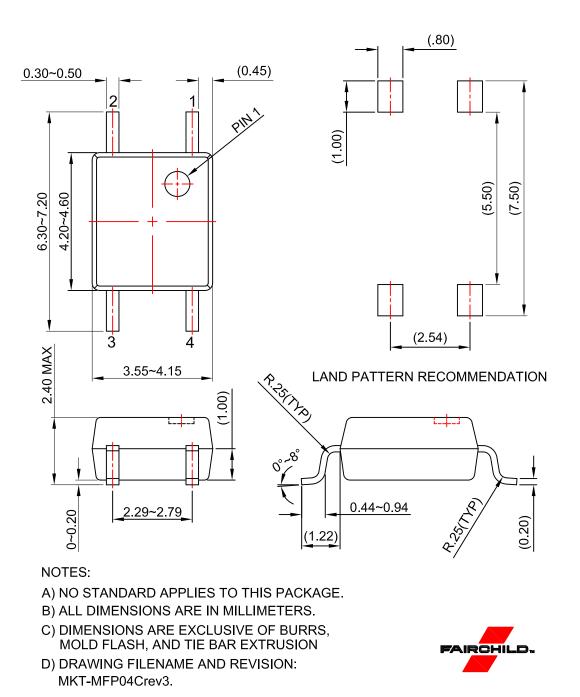
1	Fairchild Logo
2	Device Number
3	DIN EN/IEC60747-5-5 Option (only appears on component ordered with this option)
4	One-Digit Year Code, e.g., "5"
5	Digit Work Week, Ranging from "01" to "53"
6	Assembly Package Code

Carrier Tape Specifications





		2.54 Pitch
Description	Symbol	Dimensions
Tape Width	W	12.00±0.4
Tape Thickness	t	0.35±0.02
Sprocket Hole Pitch	Po	4.00±0.20
Sprocket Hole Dia.	Do	1.55±0.20
Sprocket Hole Location	E	1.75±0.20
Pocket Location	F	5.50±0.20
	P ₂	2.00±0.20
Pocket Pitch	Р	8.00±0.20
Pocket Dimension	A ₀	4.75±0.20
	B ₀	7.30±0.20
	K ₀	2.30±0.20
Pocket Hole Dia.	D ₁	1.55±0.20
Cover Tape Width	W ₁	9.20
Cover Tape Thickness	d	0.065±0.02
Max. Component Rotation or Tilt		20° max
Devices Per Reel		2500
Reel Diameter		330 mm (13")



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